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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: T. NAKATA, et al

Serial No.: 09/437,265

Filed: November 10, 1999

For: **METHOD FOR MEASURING DIMENSIONS AND ALIGNMENT OF
THIN FILM MAGNETIC HEAD AND APPARATUS THEREFOR**

Group: 2877

STATEMENT OF THE SUBSTANCE OF THE INTERVIEW

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

June 2, 2004

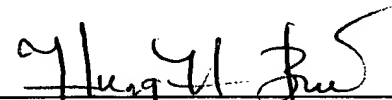
Sir:

Based on review of the Examiner's Interview Summary (Paper No. 0504)
dated May 26, 2004, Applicant agrees that the statement provided therein is true and
accurate.

Respectfully submitted,

ANTONELLI, TERRY, STOUT & KRAUS, LLP

By


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HHB:btd

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